

Search Notes



Application/Control No.

10/783,763

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

LEE, WHONCHEE

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	689	12/2/2005	KCC
438	693	12/2/05	KCC
451	287		
451	288		
451	443		
451	444		
205	662		
	670		
	671		
205	672	12/2/05	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Fast Keywords search US PAT, US PGT-pub. EP, JP, Derwent IBM TDB, inventor search	12/2/2005	KCC